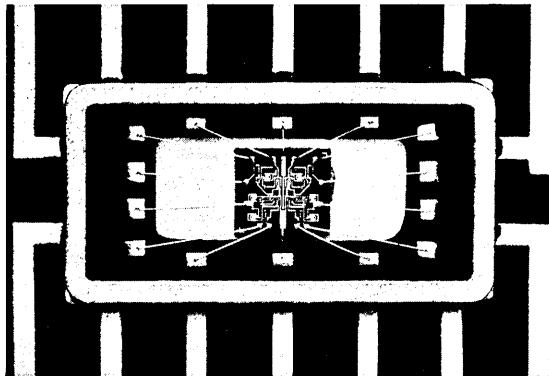




HIGH-SPEED SATURATED DIGITAL CIRCUITS FOR GENERAL-PURPOSE INDUSTRIAL APPLICATIONS

description

Series 74 integrated circuits have been designed and characterized for high-speed, general-purpose digital applications where high d-c noise margin and low power dissipation are important system considerations. Definitive specifications are provided for operating characteristics over the temperature range of 0°C to 70°C. This logic series includes the basic gating and flip-flop elements needed to perform practically all functions required of general-purpose industrial digital systems.



TYPE SN7400 PRIOR TO CAPPING

features

LOW SYSTEM COST

- maximum number of circuits per package through use of 14-lead package

OPTIMUM CIRCUIT PERFORMANCE

- high speed — typical propagation delay time 13 nsec
- high d-c noise margin — typically one volt
- low output impedance provides low a-c noise susceptibility
- waveform integrity over full range of loading and temperature conditions
- low power dissipation — 10 mw per gate at 50% duty cycle
- full fan-out of 10

CONTENTS	Page
CIRCUIT OPERATION AND DESIGN CHARACTERISTICS	2
LOGIC DEFINITION AND SYMBOLS	3
DEFINITIVE SPECIFICATIONS	4-13
D-C TEST CIRCUITS	14-18
SWITCHING TIME VOLTAGE WAVEFORMS	19-22
TYPICAL CHARACTERISTICS	23
MECHANICAL AND PACKAGING DATA	24

[†]Patented by Texas Instruments Incorporated.



TEXAS INSTRUMENTS
INCORPORATED
SEMICONDUCTOR-COMPONENTS DIVISION
POST OFFICE BOX 5012 • DALLAS 22, TEXAS

SERIES 74

SOLID CIRCUIT[®] SEMICONDUCTOR NETWORKS

design characteristics

Series 74 digital integrated circuits effect an optimization between saturated logic circuitry and monolithic semiconductor technology yielding high performance at lowest cost. In discrete component circuitry maximum use is made of lower cost components (diodes and resistors) instead of the higher priced transistors. However, in monolithic circuitry it costs no more to build transistors than diodes or resistors. Therefore, in Series 74, transistors are used to buffer the fluctuations in currents that occur as resistor values change. Also, the Series 74 multiple emitter transistor can easily be built in a monolithic bar to eliminate the need for conventional input diodes.

circuit operation

The transistor-transistor logic (TTL) used in Series 74 is analogous to diode-transistor logic (DTL) in certain respects. As shown in figure A, a low voltage at inputs A or B will allow current to flow through the diode associated with the low input, and no drive current will pass through diode D₃. If inputs A and B are raised to a high voltage, drive current will then pass through diode D₃.

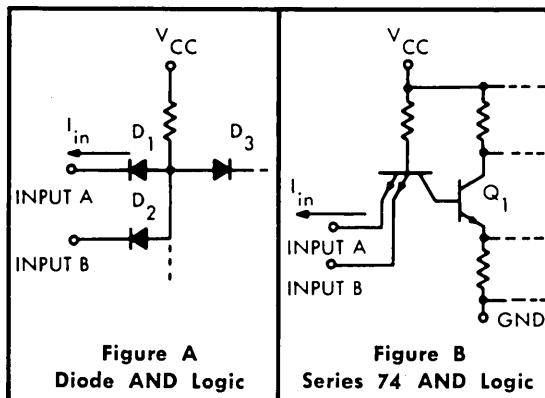


Figure A
Diode AND Logic

Figure B
Series 74 AND Logic

In Series 74 TTL circuitry, the multiple-emitter transistor performs the same function as the diodes in DTL (see figure B). However, the transistor action of the multiple-emitter transistor causes transistor Q₁ to turn-off more rapidly, thus providing an inherent switching-time advantage over the DTL circuit.

Although one-volt d-c noise margins are typical for Series 74 circuits, an absolute guarantee of 400 millivolts is assured for every unit. This is accomplished by testing each output and input as shown in figures C and D.

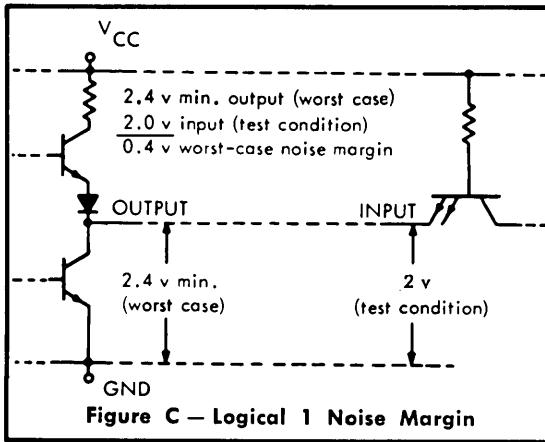


Figure C — Logical 1 Noise Margin

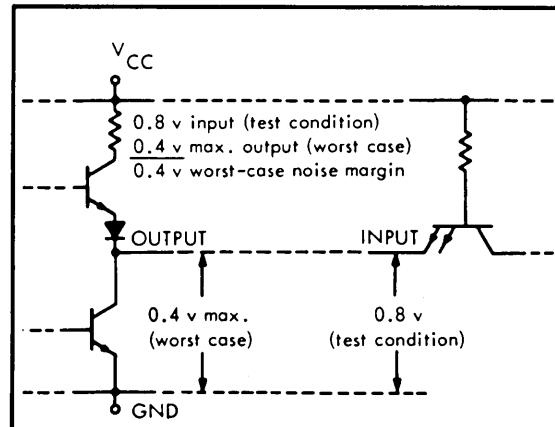


Figure D — Logical 0 Noise Margin

Each output is tested over the full temperature range to ensure that the logical 1 output voltage will not fall below 2.4 volts. This is done with full fan-out, lowest V_{CC}, and 0.8 volts on the input — 400 mv more than the logical 0 maximum.

Each output is tested over the full temperature range to ensure that the logical 0 output voltage will not exceed 0.4 volts. This is done with full fan-out, lowest V_{CC}, and 2 volts on the input — 400 mv less than the logical 1 minimum.

In actual system operation, the majority of circuits do not experience worst-case conditions of fan-out, supply voltage, temperature, and input voltage simultaneously. In addition, the threshold voltage of the Series 74 circuits is about 1.5 volts. These characteristics allow a larger voltage change on an input without false triggering. This typical noise margin is shown in figure E.

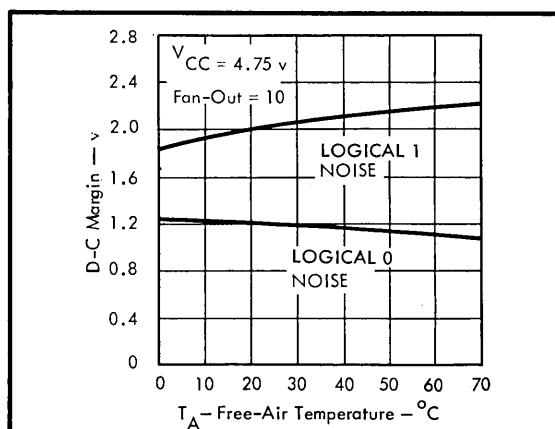


Figure E — Typical D-C Margin vs Temperature

Another important feature of the design is the output configuration which both supplies current (in the logical 1 state) and sinks current (in the logical 0 state) from a low impedance. Typically, logical 0 output impedance is 12 Ω and logical 1 output impedance is 100 Ω. This low output impedance in either state rejects capacitively coupled a-c pulses and ensures small R-C time constants which preserve wave-shape integrity.

SOLID CIRCUIT® SEMICONDUCTOR NETWORKS

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

NOTES: 1. Voltage values are with respect to network ground terminal.
2. Input signals must be zero or positive with respect to network ground terminal.

logic definition

Series 74 logic is defined in terms of standard POSITIVE LOGIC using the following definitions:

LOW VOLTAGE = LOGICAL 0

HIGH VOLTAGE = LOGICAL 1

input-current requirements

Input-current requirements reflect worst-case conditions for $T_A = 0^\circ\text{C}$ to 70°C and $V_{CC} = 4.75$ to 5.25 v. Each input of the multiple-emitter input transistor requires that no more than 1.6 mA flow out of the input at a logical 0 voltage level; therefore, one load ($N = 1$) is 1.6 mA maximum. The flip-flop preset and clear inputs supply two multiple-emitter transistors; thus, each preset or clear input is the equivalent of $N = 2$ loads. Each input requires current into the input at a logical 1 voltage level. This current is 40 μA maximum for all inputs except for the preset and clear which are 80 μA maximum.

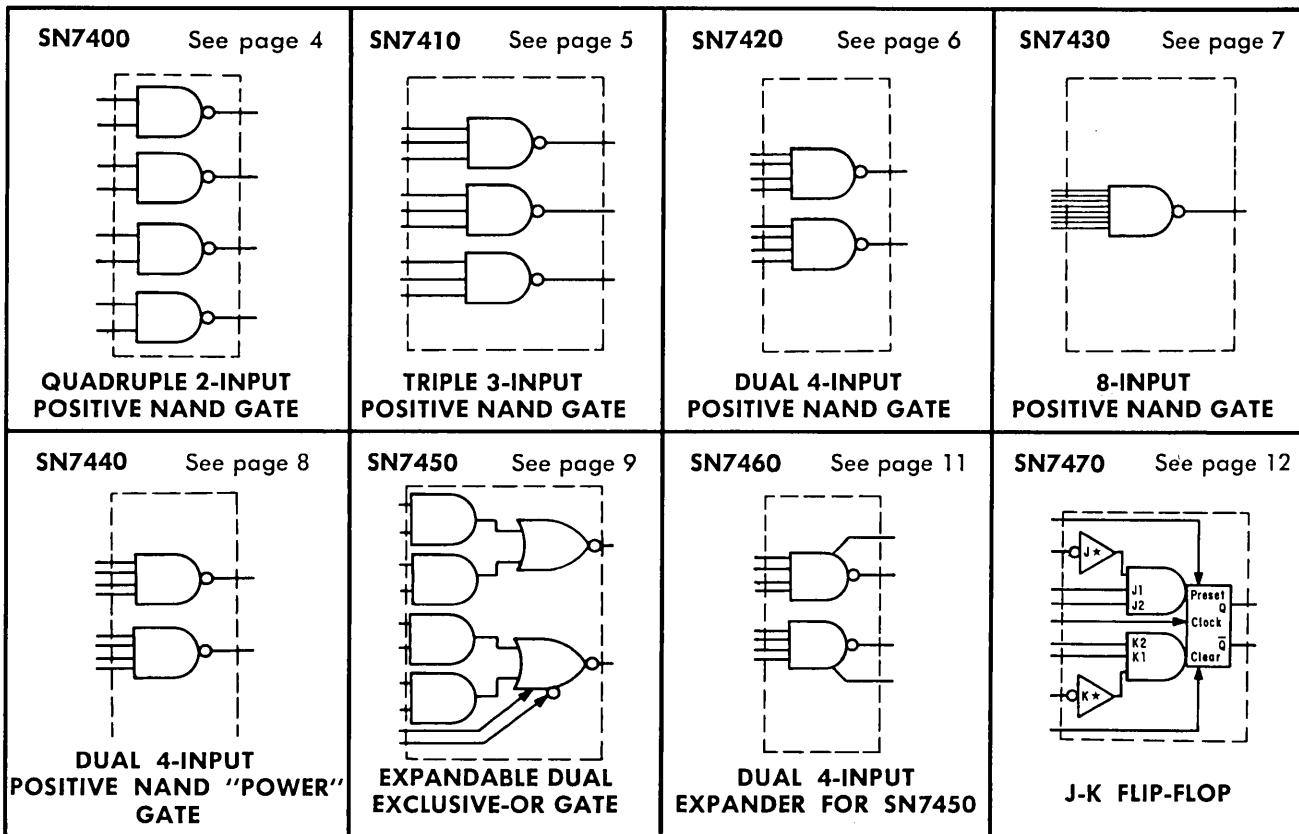
fan-out capability

Fan-out reflects the ability of an output to sink current from a number of loads (N) at a logical 0 voltage level and to supply current at a logical 1 voltage level. Each output is capable of sinking current or supplying current to 10 loads ($N = 10$). The "power" gate is capable of sinking current or supplying current to 30 loads ($N=30$).

unused inputs

All unused inputs except J★ and K★ should be connected to V_{CC}. Unused J★ or K★ input should be connected to ground.

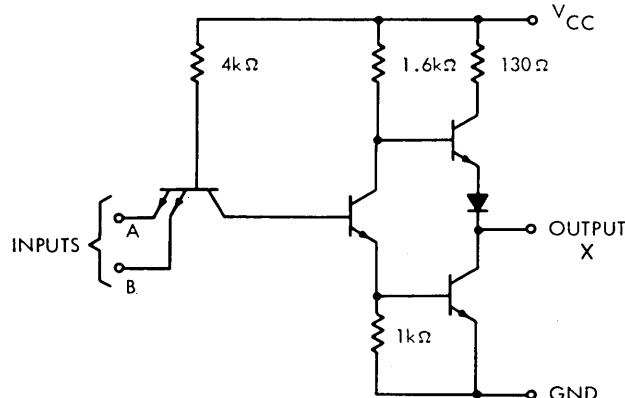
standard line summary



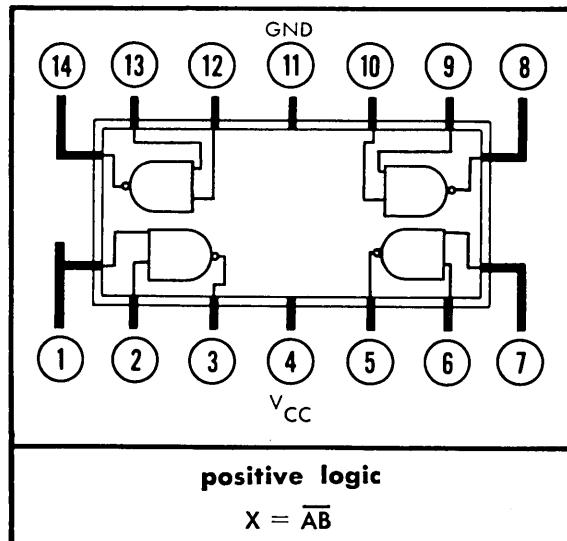
TYPE SN7400

QUADRUPLE 2-INPUT POSITIVE NAND GATE

schematic (each gate)



Component values shown are nominal.



recommended operating conditions

Supply Voltage, V_{CC}	4.75 v to 5.25 v
Maximum Fan-Out From Each Output, N	10

electrical characteristics, $T_A = 0^\circ\text{C}$ to 70°C

PARAMETER	TEST FIGURE	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$V_{in(1)}$ Logical 1 input voltage required at all input terminals that will ensure logical 0 level at output	1	$V_{CC} = 4.75 \text{ v}$, $V_{out(0)} \leq 0.4 \text{ v}$, $R = 272 \Omega$	2			v
$V_{in(0)}$ Logical 0 input voltage required at any input terminal that will ensure logical 1 level at output	2	$V_{CC} = 4.75 \text{ v}$, $V_{out(1)} \geq 2.4 \text{ v}$, $R = 6 \text{ k}\Omega$		0.8		v
$V_{out(1)}$ Logical 1 output voltage	2	$V_{CC} = 4.5 \text{ v}$, $V_{in} = 0.8 \text{ v}$, $I_{load} \geq 400 \mu\text{a}$, $R = 6 \text{ k}\Omega$	2.4			v
$V_{out(0)}$ Logical 0 output voltage	1	$V_{CC} = 4.75 \text{ v}$, $V_{in} = 2 \text{ v}$, $I_{sink} \geq 16 \text{ ma}$, $R = 272 \Omega$		0.4		v
I_{in} Input current (each input)	3	$V_{CC} = 5.25 \text{ v}$, $V_{in} = 0.4 \text{ v}$		1.6		ma
I_{in} Input current (each input)	4	$V_{CC} = 5.25 \text{ v}$, $V_{in} = 4.75 \text{ v}$		40		μa
I_{os} Short-circuit output current†	5	$V_{CC} = 5.25 \text{ v}$	18	55		ma
$I_{CC(0)}$ Logical 0 level supply current (each gate)	6	$V_{CC} = V_{in} = 5 \text{ v}$		3		ma
$I_{CC(1)}$ Logical 1 level supply current (each gate)	6	$V_{CC} = 5 \text{ v}$, $V_{in} = 0$		1		ma

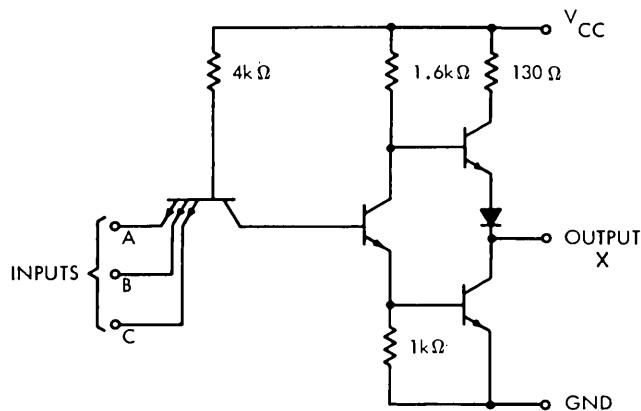
switching characteristics, $V_{CC} = 5 \text{ v}$, $T_A = 25^\circ\text{C}$

PARAMETER	TEST FIGURE	TEST CONDITIONS	TYP	MAX	UNIT
t_{d0} Propagation time to logical 0	27	$C_1 = 15 \text{ pf}$, $N = 10$	8	15	nsec
t_{d1} Propagation time to logical 1	27	$C_1 = 15 \text{ pf}$, $N = 1$	18	29	nsec

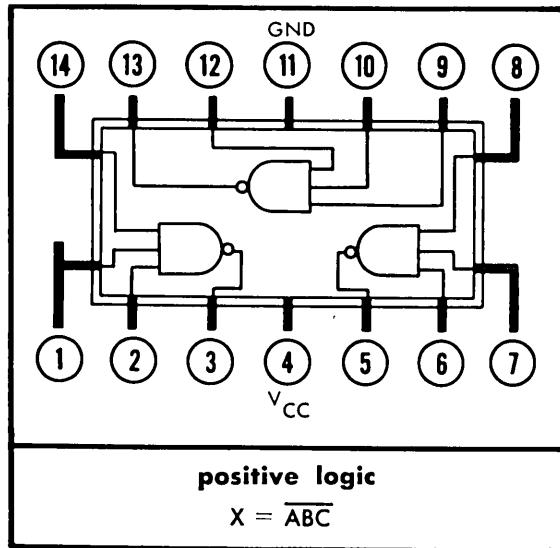
†Not more than one output should be shorted at a time.

TYPE SN7410 TRIPLE 3-INPUT POSITIVE NAND GATE

schematic (each gate)



Component values shown are nominal.



recommended operating conditions

Supply Voltage, V _{CC}	4.75 v to 5.25 v
Maximum Fan-Out From Each Output, N	10

electrical characteristics, T_A = 0°C to 70°C

PARAMETER	TEST FIGURE	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V _{in(1)} Logical 1 input voltage required at all input terminals that will ensure logical 0 level at output	1	V _{CC} = 4.75 v, V _{out(0)} ≤ 0.4 v, R = 272 Ω	2			v
V _{in(0)} Logical 0 input voltage required at any input terminal that will ensure logical 1 level at output	2	V _{CC} = 4.75 v, V _{out(1)} ≥ 2.4 v, R = 6 kΩ		0.8		v
V _{out(1)} Logical 1 output voltage	2	V _{CC} = 4.75 v, V _{in} = 0.8 v, I _{load} ≥ 400 μa, R = 6 kΩ	2.4			v
V _{out(0)} Logical 0 output voltage	1	V _{CC} = 4.75 v, V _{in} = 2 v, I _{sink} ≥ 16 ma, R = 272 Ω		0.4		v
I _{in} Input current (each input)	3	V _{CC} = 5.25 v, V _{in} = 0.4 v	1.6			ma
I _{in} Input current (each input)	4	V _{CC} = 5.25 v, V _{in} = 4.75 v		40		μa
I _{OS} Short-circuit output current†	5	V _{CC} = 5.25 v	18	55		ma
I _{CC(0)} Logical 0 level supply current (each gate)	6	V _{CC} = V _{in} = 5 v	3			ma
I _{CC(1)} Logical 1 level supply current (each gate)	6	V _{CC} = 5 v, V _{in} = 0	1			ma

switching characteristics, V_{CC} = 5 v, T_A = 25°C

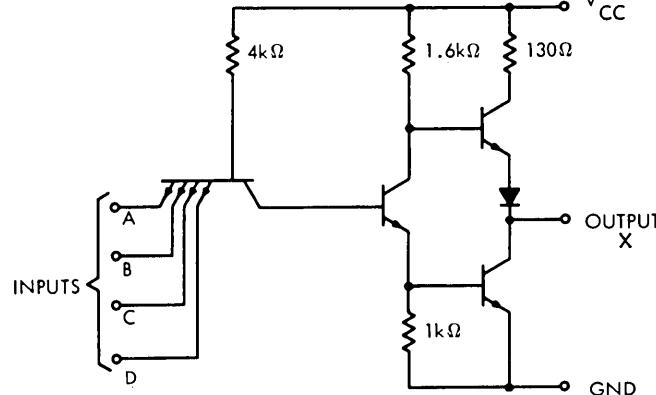
PARAMETER	TEST FIGURE	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{d0} Propagation time to logical 0	27	C ₁ = 15 pf, N = 10	8	15		nsec
t _{d1} Propagation time to logical 1	27	C ₁ = 15 pf, N = 1	18	29		nsec

†Not more than one output should be shorted at a time.

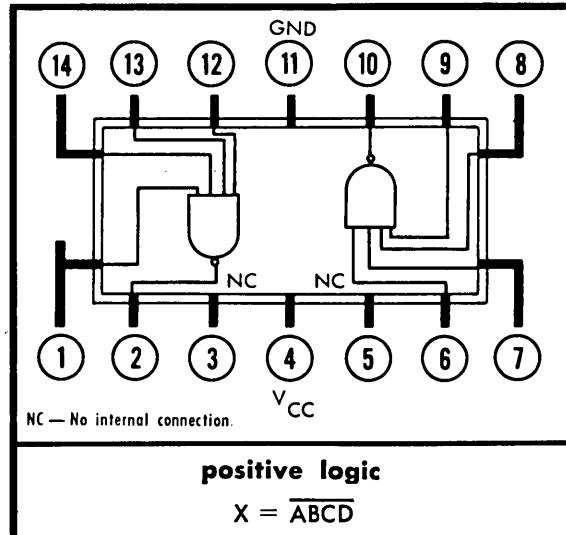
TYPE SN7420

DUAL 4-INPUT POSITIVE NAND GATE

schematic (each gate)



Component values shown are nominal.



recommended operating conditions

Supply Voltage, V _{CC}	4.75 v to 5.25 v
Maximum Fan-Out From Each Output, N	10

electrical characteristics, T_A = 0°C to 70°C

PARAMETER	TEST FIGURE	TEST CONDITIONS	MIN	TYP	MAX	UNIT
V _{in(1)} Logical 1 input voltage required at all input terminals that will ensure logical 0 level at output	1	V _{CC} = 4.75 v, V _{out(0)} ≤ 0.4 v, R = 272 Ω	2			v
V _{in(0)} Logical 0 input voltage required at any input terminal that will ensure logical 1 level at output	2	V _{CC} = 4.75 v, V _{out(1)} ≥ 2.4 v, R = 6 kΩ		0.8		v
V _{out(1)} Logical 1 output voltage	2	V _{CC} = 4.75 v, V _{in} = 0.8 v, I _{load} ≥ 400 μa, R = 6 kΩ	2.4			v
V _{out(0)} Logical 0 output voltage	1	V _{CC} = 4.75 v, V _{in} = 2 v, I _{sink} ≥ 16 ma, R = 272 Ω		0.4		v
I _{in} Input current (each input)	3	V _{CC} = 5.25 v, V _{in} = 0.4 v		1.6		ma
I _{in} Input current (each input)	4	V _{CC} = 5.25 v, V _{in} = 4.75 v		40		μa
I _{OS} Short-circuit output current†	5	V _{CC} = 5.25 v	18		55	ma
I _{CC(0)} Logical 0 level supply current (each gate)	6	V _{CC} = V _{in} = 5 v		3		ma
I _{CC(1)} Logical 1 level supply current (each gate)	6	V _{CC} = 5 v, V _{in} = 0		1		ma

switching characteristics, V_{CC} = 5 v, T_A = 25°C

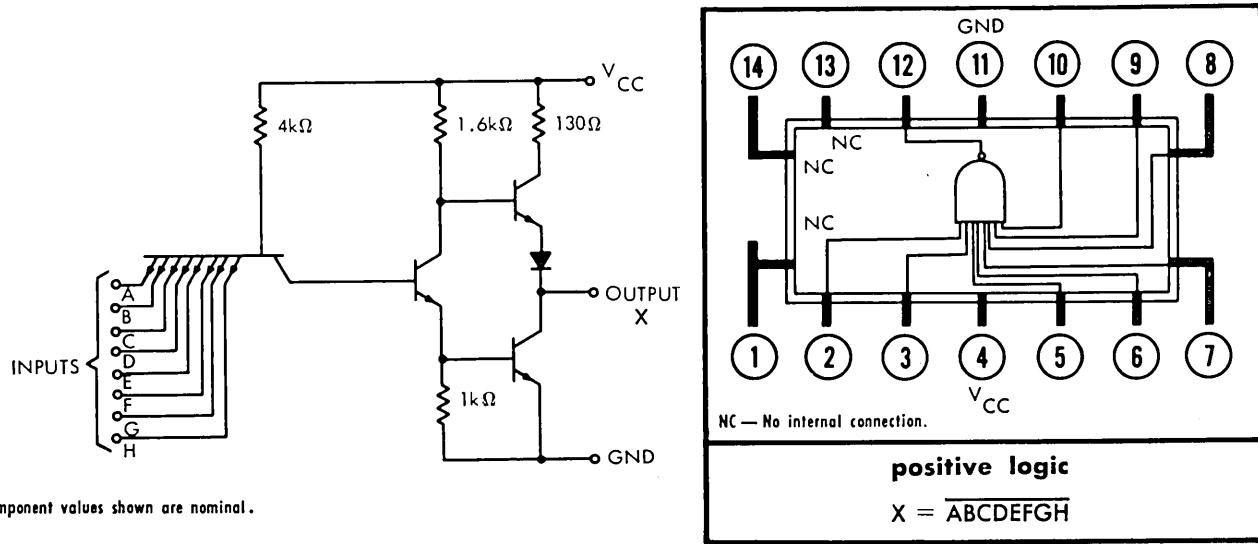
PARAMETER	TEST FIGURE	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t _{d0} Propagation time to logical 0	27	C _l = 15 pf, N = 10	8	15		nsec
t _{d1} Propagation time to logical 1	27	C _l = 15 pf, N = 1	18	29		nsec

†Not more than one output should be shorted at a time.

TYPE SN7430

8-INPUT POSITIVE NAND GATE

schematic (each gate)



recommended operating conditions

Supply Voltage, V_{CC}	4.75 v to 5.25 v
Maximum Fan-Out From Each Output, N	10

electrical characteristics, $T_A = 0^\circ C$ to $70^\circ C$

PARAMETER	TEST FIGURE	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$V_{in(1)}$ Logical 1 input voltage required at all input terminals that will ensure logical 0 level at output	1	$V_{CC} = 4.75$ v, $V_{out(0)} \leq 0.4$ v, $R = 272 \Omega$	2			v
$V_{in(0)}$ Logical 0 input voltage required at any input terminal that will ensure logical 1 level at output	2	$V_{CC} = 4.75$ v, $V_{out(1)} \geq 2.4$ v, $R = 6 k\Omega$		0.8		v
$V_{out(1)}$ Logical 1 output voltage	2	$V_{CC} = 4.75$ v, $V_{in} = 0.8$ v, $I_{load} \geq 400 \mu\text{A}$, $R = 6 k\Omega$	2.4			v
$V_{out(0)}$ Logical 0 output voltage	1	$V_{CC} = 4.75$ v, $V_{in} = 2$ v, $I_{sink} \geq 16$ ma, $R = 272 \Omega$		0.4		v
I_{in} Input current (each input)	3	$V_{CC} = 5.25$ v, $V_{in} = 0.4$ v		1.6		ma
I_{in} Input current (each input)	4	$V_{CC} = 5.25$ v, $V_{in} = 4.75$ v		40		μA
I_{OS} Short-circuit output current	5	$V_{CC} = 5.25$ v	18	55		ma
$I_{CC(0)}$ Logical 0 level supply current (each gate)	6	$V_{CC} = V_{in} = 5$ v		3		ma
$I_{CC(1)}$ Logical 1 level supply current (each gate)	6	$V_{CC} = 5$ v, $V_{in} = 0$		1		ma

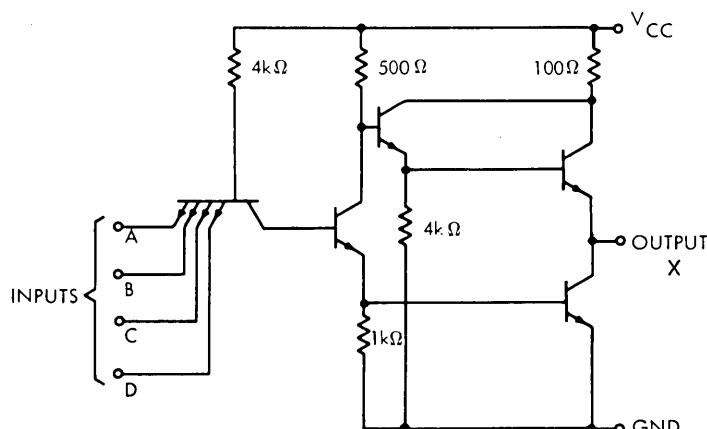
switching characteristics, $V_{CC} = 5$ v, $T_A = 25^\circ C$

PARAMETER	TEST FIGURE	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_{d0} Propagation time to logical 0	27	$C_1 = 15$ pf, $N = 10$	8	15		nsec
t_{d1} Propagation time to logical 1	27	$C_1 = 15$ pf, $N = 1$	18	29		nsec

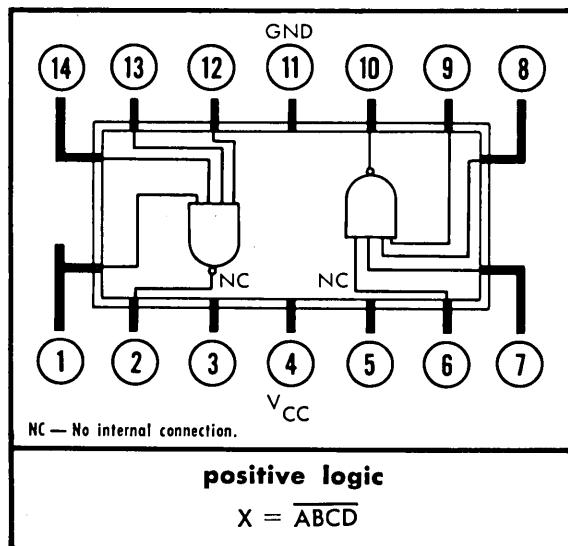
TYPE SN7440

DUAL 4-INPUT POSITIVE NAND "POWER" GATE

schematic (each gate)



Component values shown are nominal



recommended operating conditions

Supply Voltage, V_{CC}	4.75 v to 5.25 v
Maximum Fan-Out From Each Output, N	30

electrical characteristics, $T_A = 0^\circ\text{C}$ to 70°C

PARAMETER	TEST FIGURE	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$V_{in(1)}$ Logical 1 input voltage required at all input terminals that will ensure logical 0 level at output	1	$V_{CC} = 4.75 \text{ v}, V_{out(0)} \leq 0.4 \text{ v}, R = 90 \Omega$	2			v
$V_{in(0)}$ Logical 0 input voltage required at any input terminal that will ensure logical 1 level at output	2	$V_{CC} = 4.75 \text{ v}, V_{out(1)} \geq 2.4 \text{ v}, R = 2 \text{ k } \Omega$		0.8		v
$V_{out(1)}$ Logical 1 output voltage	2	$V_{CC} = 4.75 \text{ v}, V_{in} = 0.8 \text{ v}, I_{load} \geq 1.2 \text{ ma}, R = 2 \text{ k } \Omega$	2.4			v
$V_{out(0)}$ Logical 0 output voltage	1	$V_{CC} = 4.75 \text{ v}, V_{in} = 2 \text{ v}, I_{sink} \geq 16 \text{ ma}, R = 90 \Omega$		0.4		v
I_{in} Input current (each input)	3	$V_{CC} = 5.25 \text{ v}, V_{in} = 0.4 \text{ v}$		1.6		ma
I_{in} Input current (each input)	4	$V_{CC} = 5.25 \text{ v}, V_{in} = 4.75 \text{ v}$		40		μa
I_{OS} Short-circuit output current†	5	$V_{CC} = 5.25 \text{ v}$	18	70		ma
$I_{CC(0)}$ Logical 0 level supply current (each gate)	6	$V_{CC} = V_{in} = 5 \text{ v}$		8.6		ma
$I_{CC(1)}$ Logical 1 level supply current (each gate)	6	$V_{CC} = 5 \text{ v}, V_{in} = 0$		2		ma

switching characteristics, $V_{CC} = 5 \text{ v}$, $T_A = 25^\circ\text{C}$

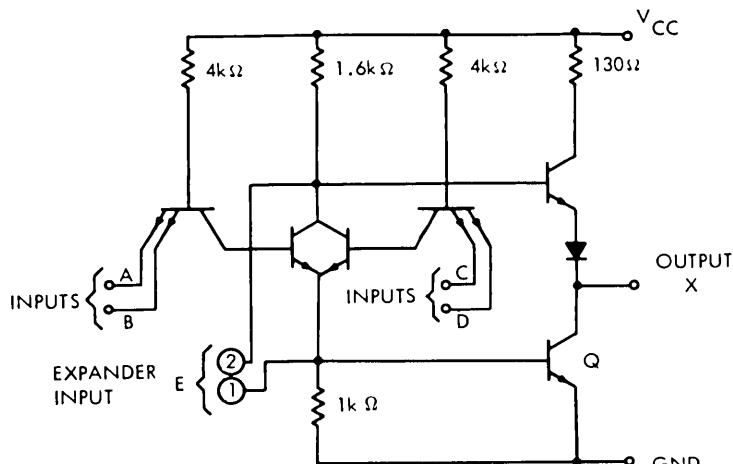
PARAMETER	TEST FIGURE	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_{d0} Propagation time to logical 0	27	$C_1 = 15 \text{ pf}, N = 10$	8	15		nsec
t_{d1} Propagation time to logical 1	27	$C_1 = 15 \text{ pf}, N = 1$	18	29		nsec

†Not more than one output should be shorted at a time.

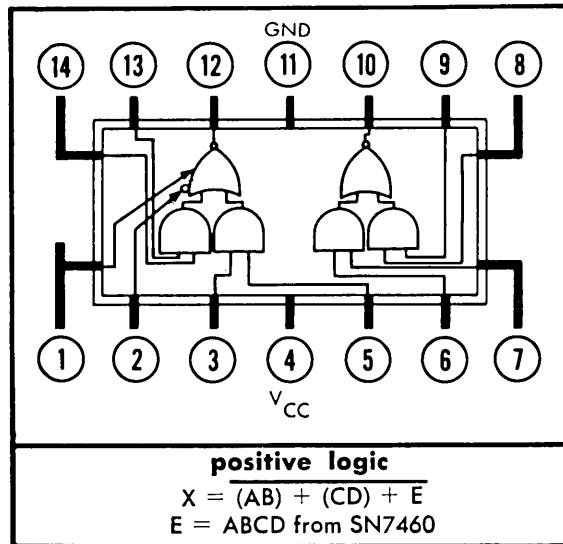
TYPE SN7450

EXPANDABLE DUAL EXCLUSIVE-OR GATE

schematic (each gate)



- NOTES:
1. Component values shown are nominal.
 2. Both expander inputs are used simultaneously for expanding with the SN7460.
 3. If expander is not used leave pins ① and ② open.



recommended operating conditions

Supply Voltage, V_{CC}	4.75 v to 5.25 v
Maximum Fan-Out From Each Output, N	10

electrical characteristics, $T_A = - 0^\circ\text{C}$ to 70°C , pins ① and ② open

PARAMETER	TEST FIGURE	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$V_{in(1)}$ Logical 1 input voltage required at all input terminals that will ensure logical 0 level at output	7	$V_{CC} = 4.75 \text{ v}, V_{out(0)} \leq 0.4 \text{ v}, R = 272 \Omega$	2			v
$V_{in(0)}$ Logical 0 input voltage required at any input terminal that will ensure logical 1 level at output	8	$V_{CC} = 4.75 \text{ v}, V_{out(1)} \geq 2.4 \text{ v}, R = 6 \text{ k}\Omega$		0.8		v
$V_{out(1)}$ Logical 1 output voltage	8	$V_{CC} = 4.75 \text{ v}, V_{in} = 0.8 \text{ v}, I_{load} \geq 400 \mu\text{a}, R = 6 \text{ k}\Omega$	2.4			v
$V_{out(0)}$ Logical 0 output voltage	7	$V_{CC} = 4.75 \text{ v}, V_{in} = 2 \text{ v}, I_{sink} \geq 16 \text{ ma}, R = 272 \Omega$		0.4		v
I_{in} Input current (each input)	9	$V_{CC} = 5.25 \text{ v}, V_{in} = 0.4 \text{ v}$		1.6		ma
I_{in} Input current (each input)	10	$V_{CC} = 5.25 \text{ v}, V_{in} = 4.75 \text{ v}$		40		μa
I_{OS} Short-circuit output current†	11	$V_{CC} = 5.25 \text{ v}$	18	55		ma
$I_{CC(0)}$ Logical 0 level supply current (each gate)	12	$V_{CC} = V_{in} = 5 \text{ v}$		3.7		ma
$I_{CC(1)}$ Logical 1 level supply current (each gate)	13	$V_{CC} = 5 \text{ v}, V_{in} = 0$	2			ma

†Not more than one output should be shorted at a time.

TYPE SN7450

EXPANDABLE DUAL EXCLUSIVE-OR GATE

electrical characteristics using expander inputs, $T_A = 0^\circ\text{C}$

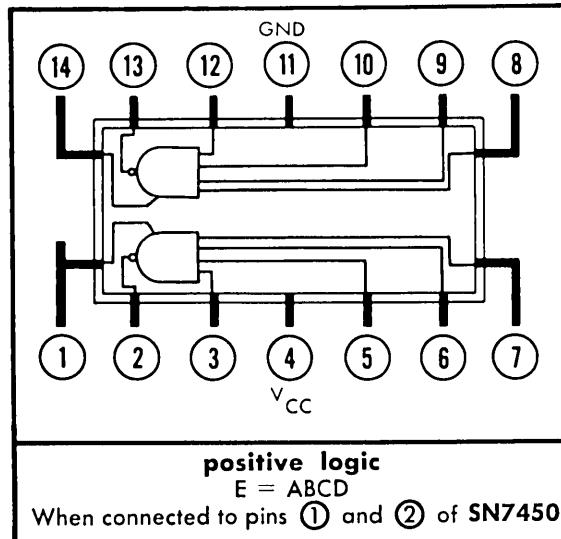
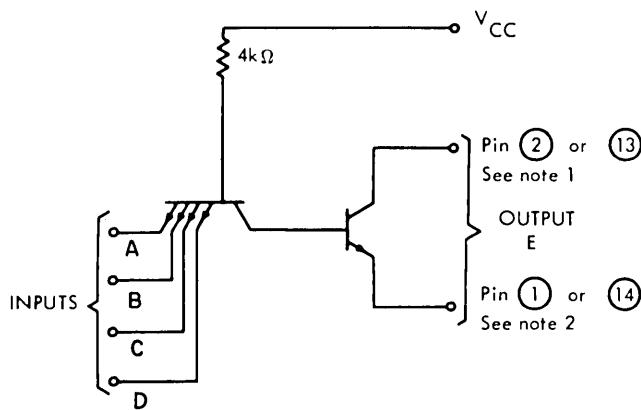
PARAMETER	TEST FIGURE	TEST CONDITIONS	MIN	MAX	UNIT
$I_{(X)}$ Expander current	14	$V_{CC} = 4.75 \text{ v}, V_1 = 0.4 \text{ v}, I_{sink} = 16 \text{ ma}$	1.5	3.1	ma
$V_{BE(Q)}$ Output transistor (Q) base-emitter voltage	15	$V_{CC} = 4.75 \text{ v}, V_2 = 1.4 \text{ v}, I_{sink} = 16 \text{ ma}, I_1 = 1.7 \text{ ma}, R = 272 \Omega$	1	v	
$V_{out(0)}$ Logical 0 output voltage	15	$V_{CC} = 4.75 \text{ v}, V_2 = 1.4 \text{ v}, I_{sink} = 16 \text{ ma}, I_1 = 1.7 \text{ ma}, R = 272 \Omega$	0.4	v	
$V_{out(1)}$ Logical 1 output voltage	16	$V_{CC} = 4.75 \text{ v}, I_{load} = 400 \mu\text{a}$ $I_1 = 0.27 \text{ ma}, I_2 = 0.27 \text{ ma}, R = 6 \text{ k} \Omega$	2.4		v

switching characteristics, $V_{CC} = 5 \text{ v}, T_A = 25^\circ\text{C}$

PARAMETER	TEST FIGURE	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_{d0} Propagation time to logical 0	27	$C_1 = 15 \text{ pf}, N = 10$	8	15		nsec
t_{d1} Propagation time to logical 1	27	$C_1 = 15 \text{ pf}, N = 1$	18	29		nsec

TYPE SN7460

schematic



NOTES: 1. Connect pin ② or ⑬ to pin ② of SN7450.
 2. Connect pin ① or ⑭ to pin ① of SN7450.
 3. Component values shown are nominal.

recommended operating conditions

electrical characteristics (unless otherwise noted $T_A = 0^\circ\text{C}$ to 70°C)

PARAMETER	TEST FIGURE	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$V_{in(1)}$	Logical 1 input voltage required at all input terminals that will ensure output on level	17	$V_{CC} = 4.75 \text{ v}$, $V_{in} = 2 \text{ v}$, $V_1 = 1 \text{ v}$, $R = 1.1 \text{ k } \Omega$, $T_A = 0^\circ\text{C}$	2		v
$V_{in(0)}$	Logical 0 input voltage at any input terminal that will ensure output off level current	18	$V_{CC} = 4.75 \text{ v}$, $V_{in} = 0.8 \text{ v}$, $V_1 = 4.75 \text{ v}$, $R = 1.2 \text{ k } \Omega$, $I_{off} = 0.27 \text{ ma}$, $T_A = 0^\circ\text{C}$		0.8	v
V_{on}	Output voltage on level	17	$V_{CC} = 4.75 \text{ v}$, $V_{in} = 2 \text{ v}$, $V_1 = 1 \text{ v}$, $R = 1.1 \text{ k } \Omega$, $T_A = 0^\circ\text{C}$		0.4	v
I_{off}	Output off level current	18	$V_{CC} = 4.75 \text{ v}$, $V_{in} = 0.8 \text{ v}$, $V_1 = 4.75 \text{ v}$, $R = 1.2 \text{ k } \Omega$, $T_A = 0^\circ\text{C}$		270	μa
I_{on}	Output on level current	19	$V_{CC} = 4.75 \text{ v}$, $V_{in} = 2 \text{ v}$, $V_1 = 1 \text{ v}$, $I_2 = 1.5 \text{ ma}$	1.7		ma
I_{in}	Input current (each input)	18	$V_{CC} = 5.25 \text{ v}$, $V_{in} = 0.4 \text{ v}$		1.6	ma
I_{in}	Input current (each input)	20	$V_{CC} = 5.25 \text{ v}$, $V_{in} = 4.75 \text{ v}$, $T_A = 70^\circ\text{C}$		40	μa
$I_{CC(on)}$	On level supply current (each gate)	21	$V_{CC} = V_{in} = 5 \text{ v}$, $V_1 = 0.85 \text{ v}$		0.6	ma
$I_{CC(off)}$	Off level supply current (each gate)	21	$V_{CC} = 5 \text{ v}$, $V_{in} = 0$, $V_1 = 0.85 \text{ v}$		1	ma

switching characteristics, $V_{CC} = 5$ v, $T_A = 25^\circ\text{C}$

PARAMETER	TEST FIGURE	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_{d0}	Propagation time to logical 0 (through SN7450)	28	$C_1 = 15 \text{ pf}$, $N = 10$	10	20	nsec
t_{d1}	Propagation time to logical 1 (through SN7450)	28	$C_1 = 15 \text{ pf}$, $N = 1$	20	34	nsec

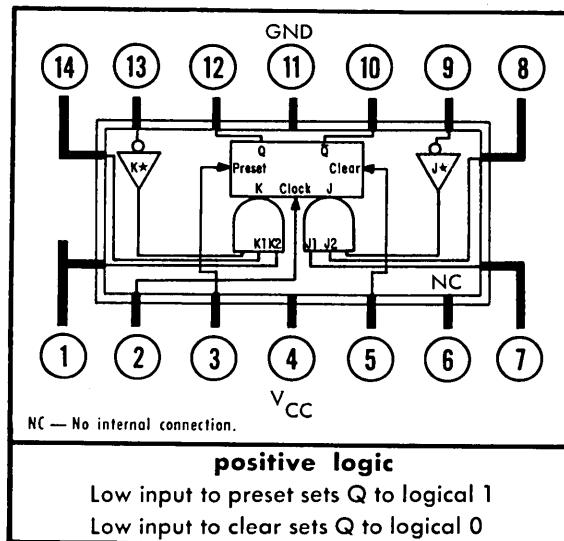
TYPE SN7470

J-K FLIP-FLOP

logic

TRUTH TABLE		
t_n	t_{n+1}	
J	K	Q
0	0	Q_n
0	1	0
1	0	1
1	1	\bar{Q}_n

- NOTES:
1. $J = J_1 \cdot J_2 \cdot \bar{J}^*$
 2. $K = K_1 \cdot K_2 \cdot \bar{K}^*$
 3. t_n = Bit time before clock pulse.
 4. t_{n+1} = Bit time after clock pulse.
 5. If inputs J^* or K^* are not used they must be grounded.



recommended operating conditions

Supply Voltage, V_{CC}	4.75 v to 5.25 v
Maximum Fan-Out From Each Output, N	10
Maximum Rise Time of Clock Pulse, $t_{r(clock)}$	150 nsec
Minimum Width of Clock Pulse, $t_{p(clock)}$	20 nsec
Toggle Frequency, f_{toggle}	0 to 25 Mc
Minimum Set-Up Time At Inputs J^* or K^* ; t_{set-up}	20 nsec
Minimum Hold Time At Inputs J_1 , J_2 , K_1 , or K_2 ; t_{hold}	15 nsec
Minimum Preset Time, t_{preset}	25 nsec
Minimum Clear Time, t_{clear}	25 nsec

electrical characteristics (unless otherwise noted $V_{CC} = 4.75$ v to 5.25 v, $T_A = 0^\circ\text{C}$ to 70°C)

PARAMETER	TEST FIGURE	TEST CONDITIONS	MIN	TYP	MAX	UNIT
$V_{in(1)}$ Input voltage that will ensure logical 1 at any input terminal	22	$V_{CC} = 4.75$ v		2		v
$V_{in(0)}$ Input voltage that will ensure logical 0 at any input terminal	22	$V_{CC} = 5.25$ v		0.8		v
$V_{out(1)}$ Logical 1 output voltage	22	$V_{CC} = 4.75$ v, $I_{load} = 400 \mu\text{A}$, $R = 6 \text{ k}\Omega$	2.4			v
$V_{out(0)}$ Logical 0 output voltage	23	$V_{CC} = 4.75$ v, $I_{sink} = 16 \text{ mA}$, $R = 272 \Omega$		0.4		v
I_{in} J_1 , J_2 , J^* , K_1 , K_2 , K^* or clock input current	24	$V_{CC} = 5.25$ v, $V_{in} = 0.4$ v		1.6		ma
I_{in} Preset or clear input current	24	$V_{CC} = 5.25$ v, $V_{in} = 0.4$ v		3.2		ma
I_{in} J_1 , J_2 , J^* , J_1 , K_2 , K^* , or clock input current	25	$V_{CC} = 5.25$ v, $V_{in} = 4.75$ v, $T_A = 70^\circ\text{C}$		40		μA
I_{in} Preset or clear input current	25	$V_{CC} = 5.25$ v, $V_{in} = 4.75$ v, $T_A = 70^\circ\text{C}$		80		μA
I_{OS} Short-circuit output current†	26	$V_{CC} = 5.25$ v, $V_{in} = 0$	18	57		ma
$I_{CC(av)}$ Average supply current	25	$V_{CC} = V_{in} = 5$ v		14		ma

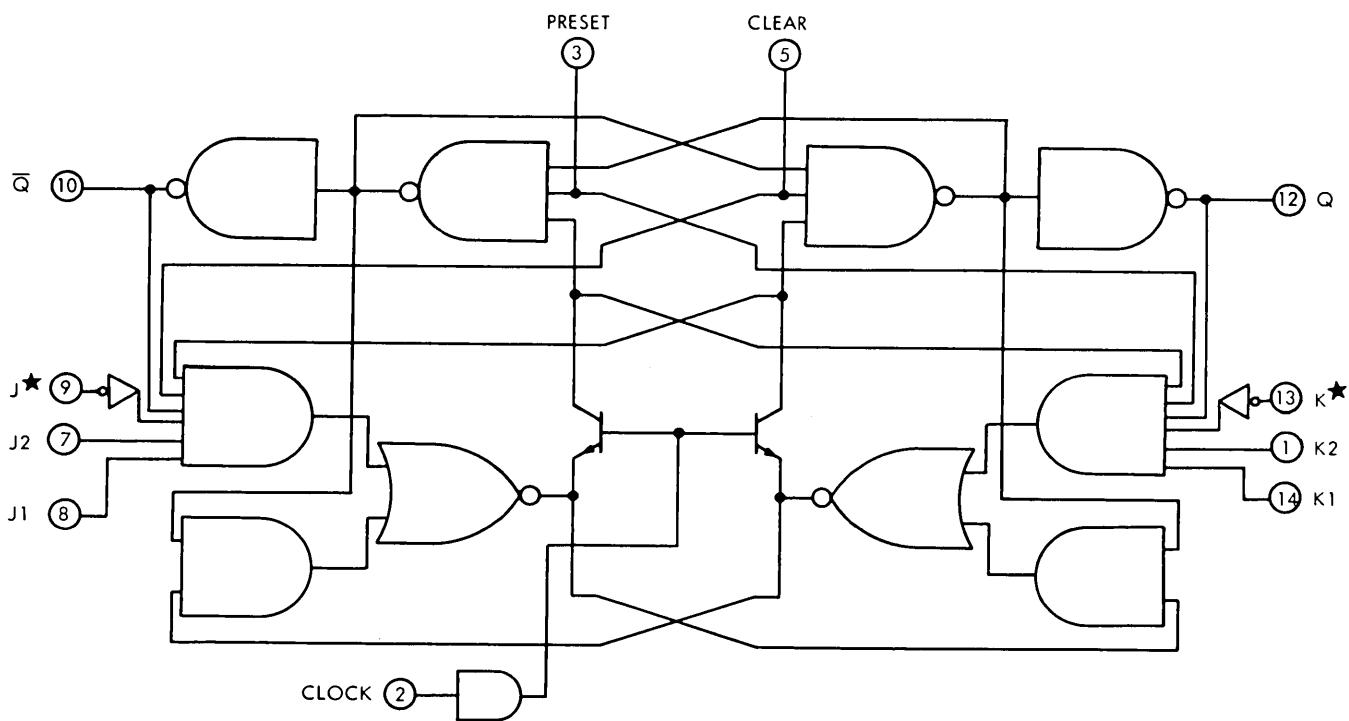
†Not more than one output should be shorted at a time.

TYPE SN7470
J-K FLIP-FLOP

switching characteristics, $V_{CC} = 5 \text{ v}$, $T_A = 25^\circ\text{C}$

PARAMETER	TEST FIGURE	TEST CONDITIONS	MIN	TYP	MAX	UNIT
t_{set-up} Minimum Input Set-Up Time	29			15		nsec
t_{hold} Minimum Input Hold Time				10		nsec
t_{preset} Minimum Preset Time	30			15		nsec
t_{clear} Minimum Clear Time				15		nsec
t_{d0} Propagation time to logical 0	29	$C_1 = 15 \text{ pf}, N = 10$	30	50		nsec
t_{d1} Propagation time to logical 1	29	$C_1 = 15 \text{ pf}, N = 1$	30	50		nsec

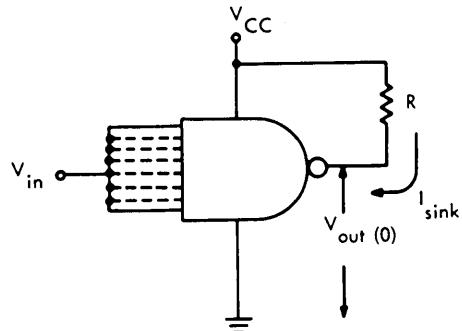
functional block diagram



SERIES 74 SOLID CIRCUIT[®] SEMICONDUCTOR NETWORKS

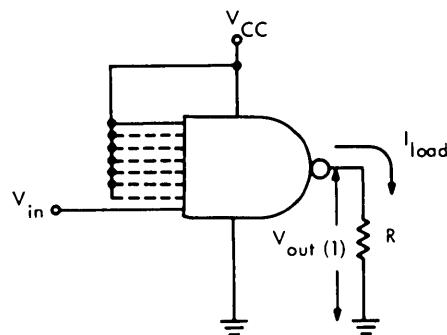
PARAMETER MEASUREMENT INFORMATION

d-c test circuits



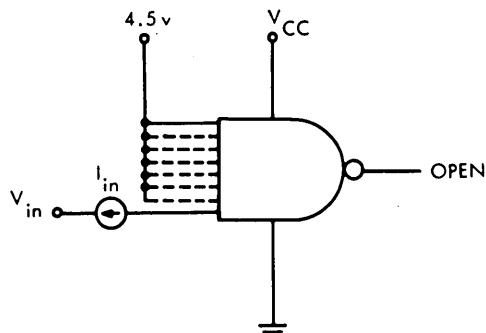
1. All inputs tested simultaneously.

FIGURE 1



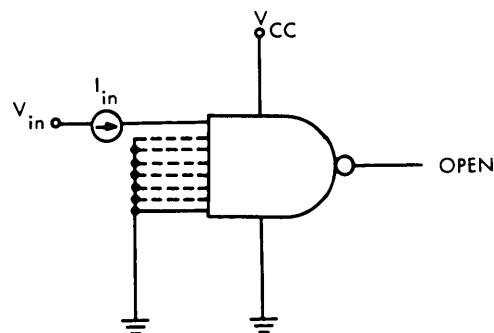
1. Each input tested separately.

FIGURE 2



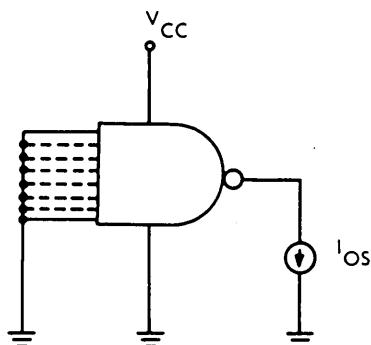
1. Each input tested separately.

FIGURE 3



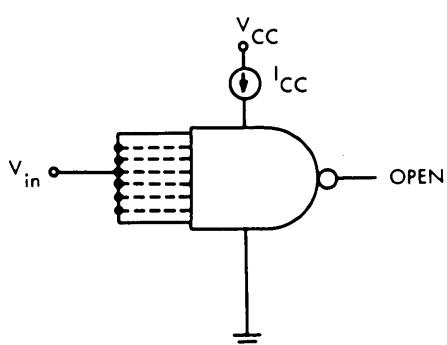
1. Each input tested separately.

FIGURE 4



1. Each gate tested separately.

FIGURE 5



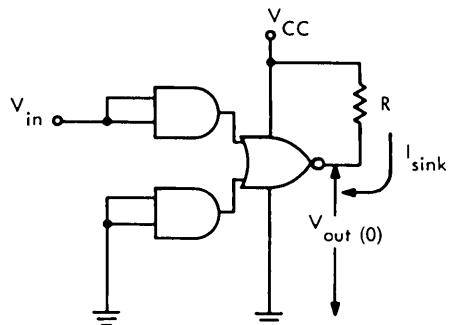
1. Test logical 0 and logical 1 conditions.

FIGURE 6

SERIES 74
SOLID CIRCUIT® SEMICONDUCTOR NETWORKS

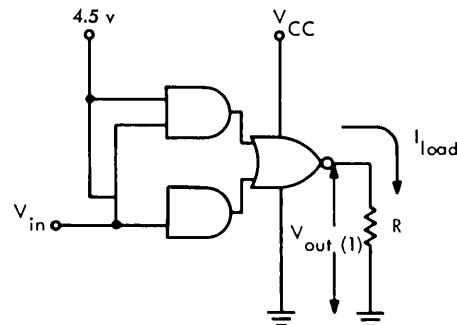
PARAMETER MEASUREMENT INFORMATION

d-c test circuits (continued)



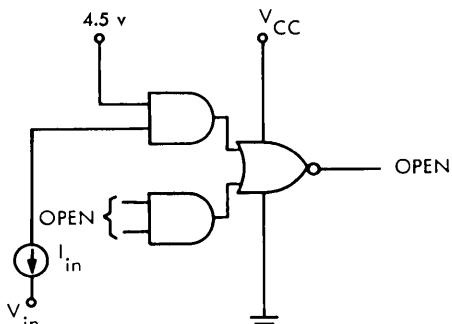
1. Each AND section tested separately.

FIGURE 7



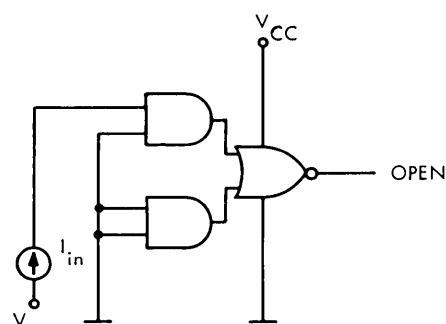
1. Each pair of inputs tested separately.

FIGURE 8



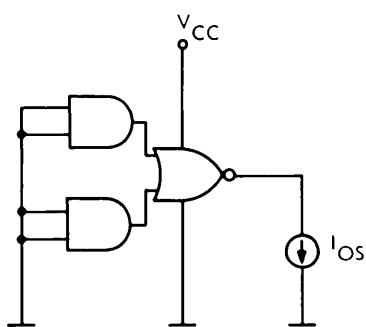
1. Each input tested separately.

FIGURE 9



1. Each input tested separately.

FIGURE 10



1. Each gate tested separately.

FIGURE 11

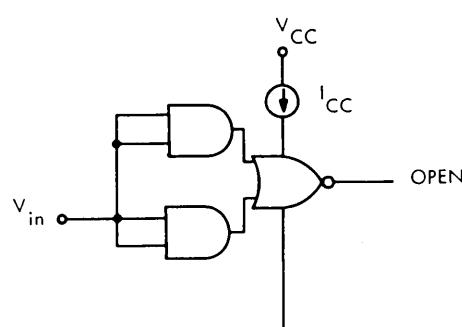


FIGURE 12

PARAMETER MEASUREMENT INFORMATION

d-c test circuits (continued)

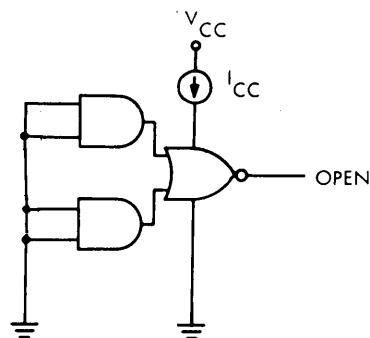


FIGURE 13

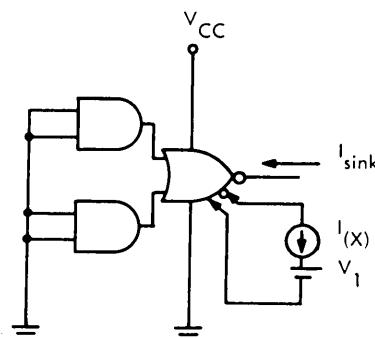


FIGURE 14

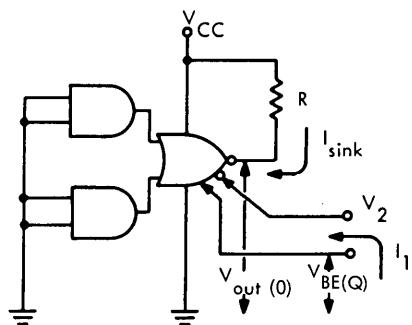


FIGURE 15

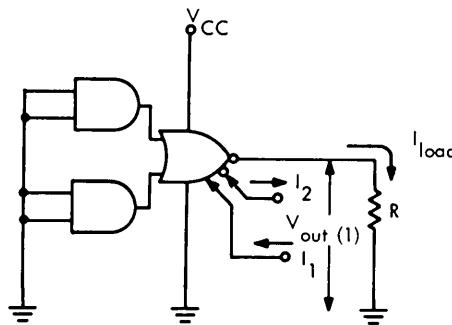
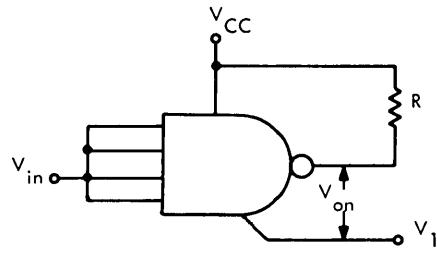
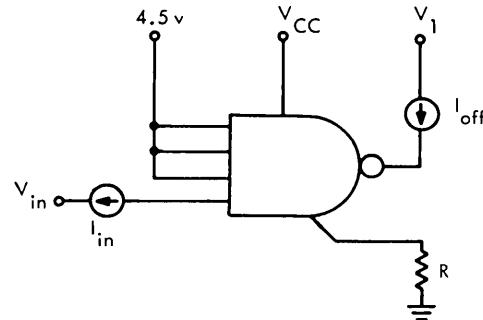


FIGURE 16



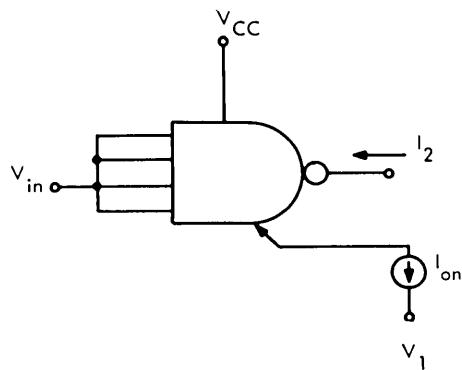
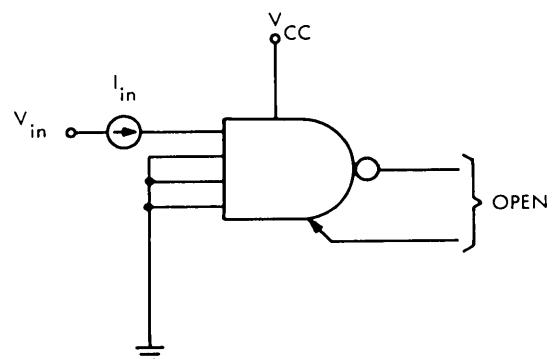
1. All inputs tested simultaneously.

FIGURE 17

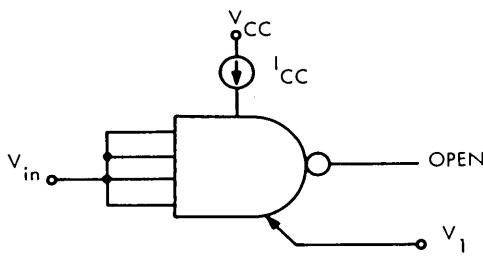


1. Each input tested separately.

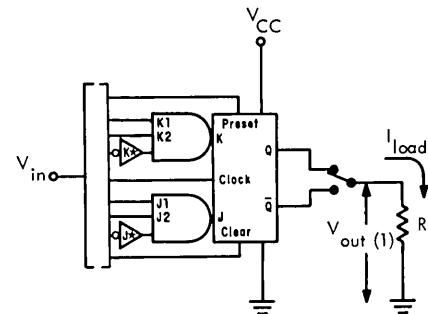
FIGURE 18

PARAMETER MEASUREMENT INFORMATION**d-c test circuits (continued)****FIGURE 19**

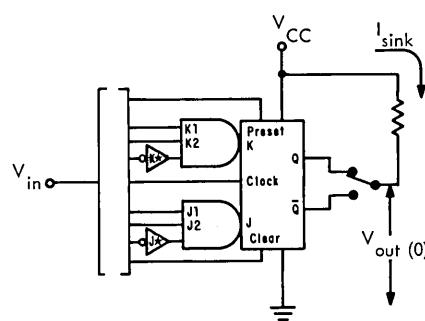
1. Each input tested separately.

FIGURE 20

1. Test "on" and "off" conditions.

FIGURE 21

1. Each output is tested separately.
2. The flip-flop is tested to ensure conformance to truth table.
3. Preset and clear are tested with $V_{in(clock)} = 0$.
4. All unused inputs are connected to worst case voltages.

FIGURE 22

1. Each output is tested separately.

FIGURE 23

SERIES 74
SOLID CIRCUIT® SEMICONDUCTOR NETWORKS

PARAMETER MEASUREMENT INFORMATION

d-c test circuits (continued)

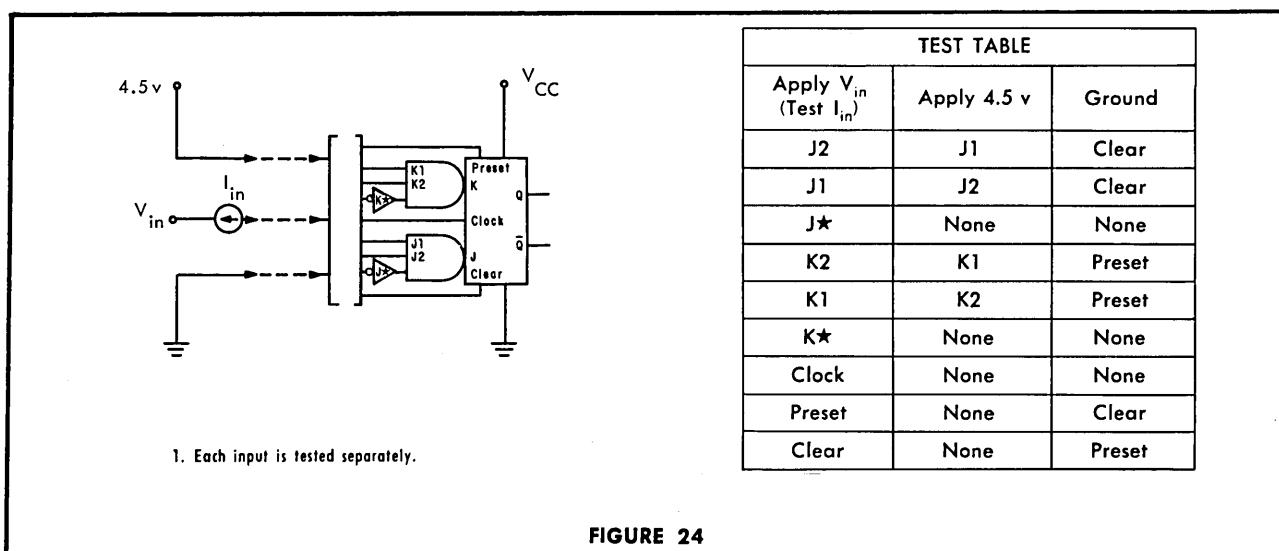


FIGURE 24

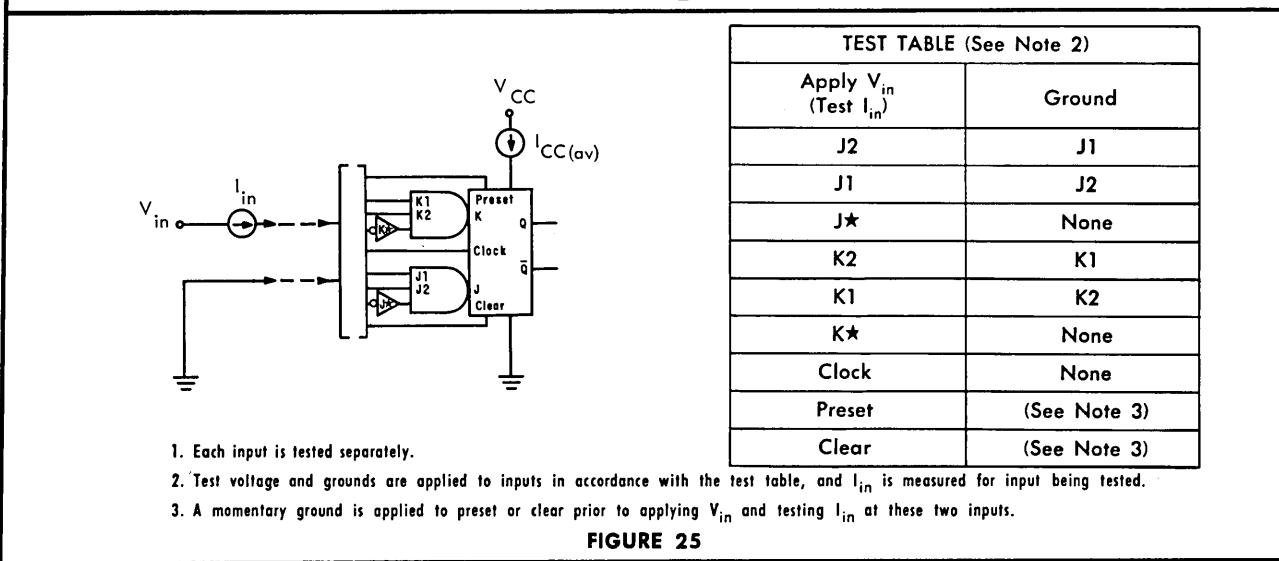


FIGURE 25

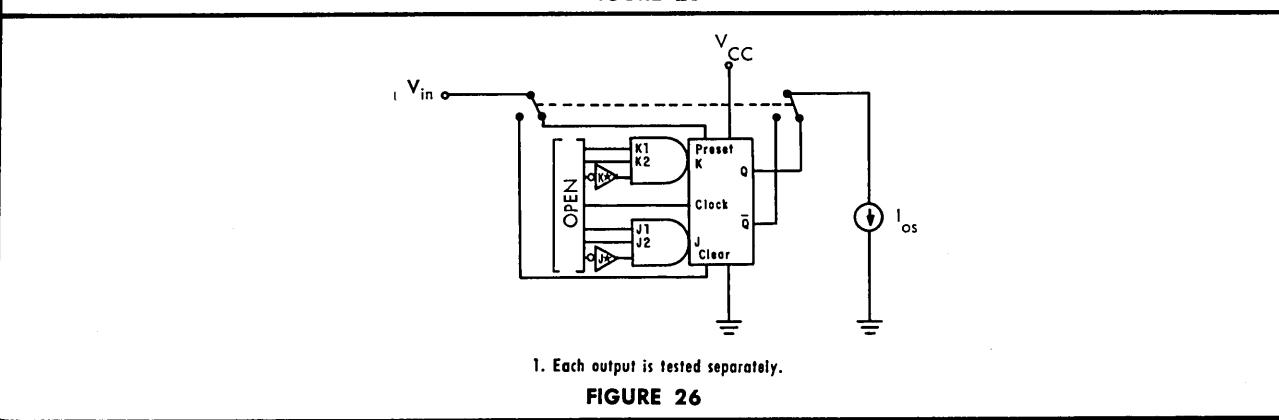
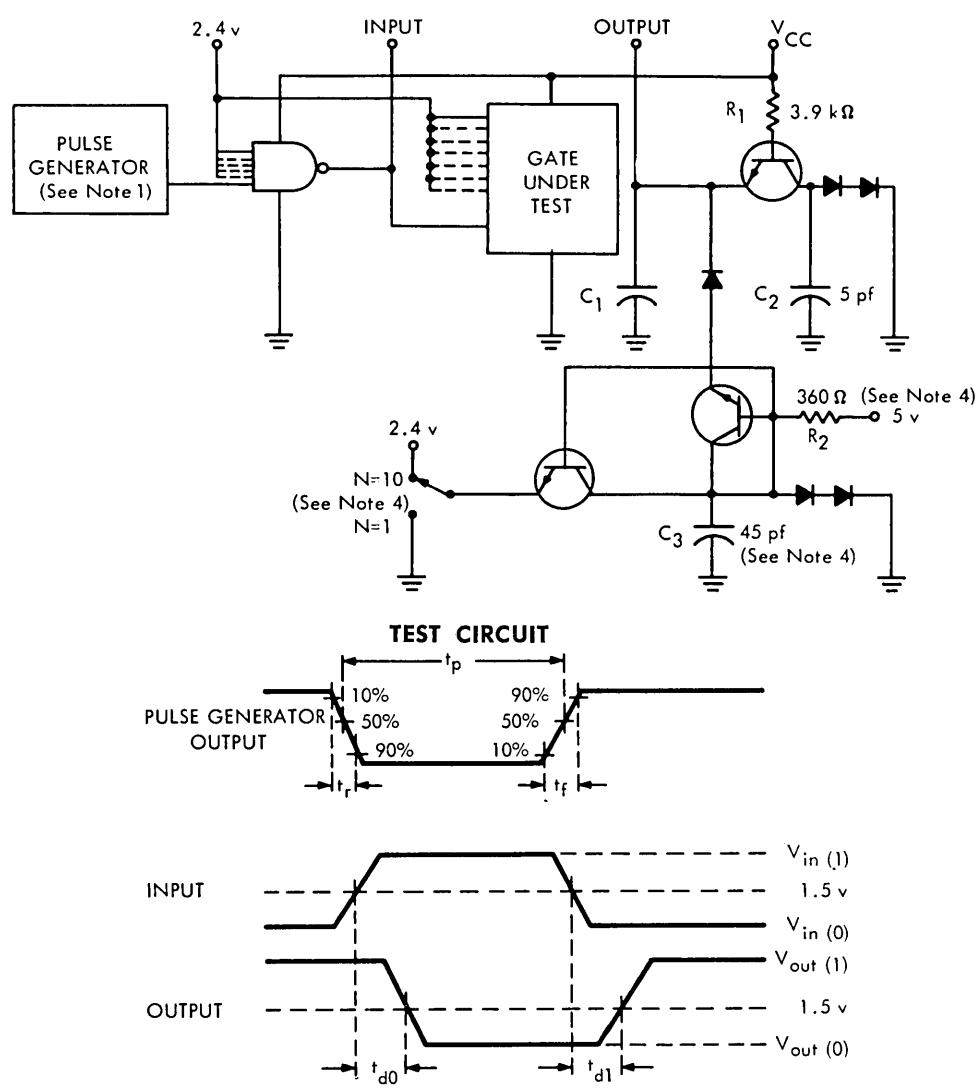


FIGURE 26

PARAMETER MEASUREMENT INFORMATION

switching characteristics



NOTES: 1. The generator has the following characteristics: t_r = t_f ≤ 15 nsec, t_p = 9.5 μsec, PRR = 100 kc, Z_{out} ≈ 50 Ω.

2. All transistors are 2N2368.

3. All diodes are IN916.

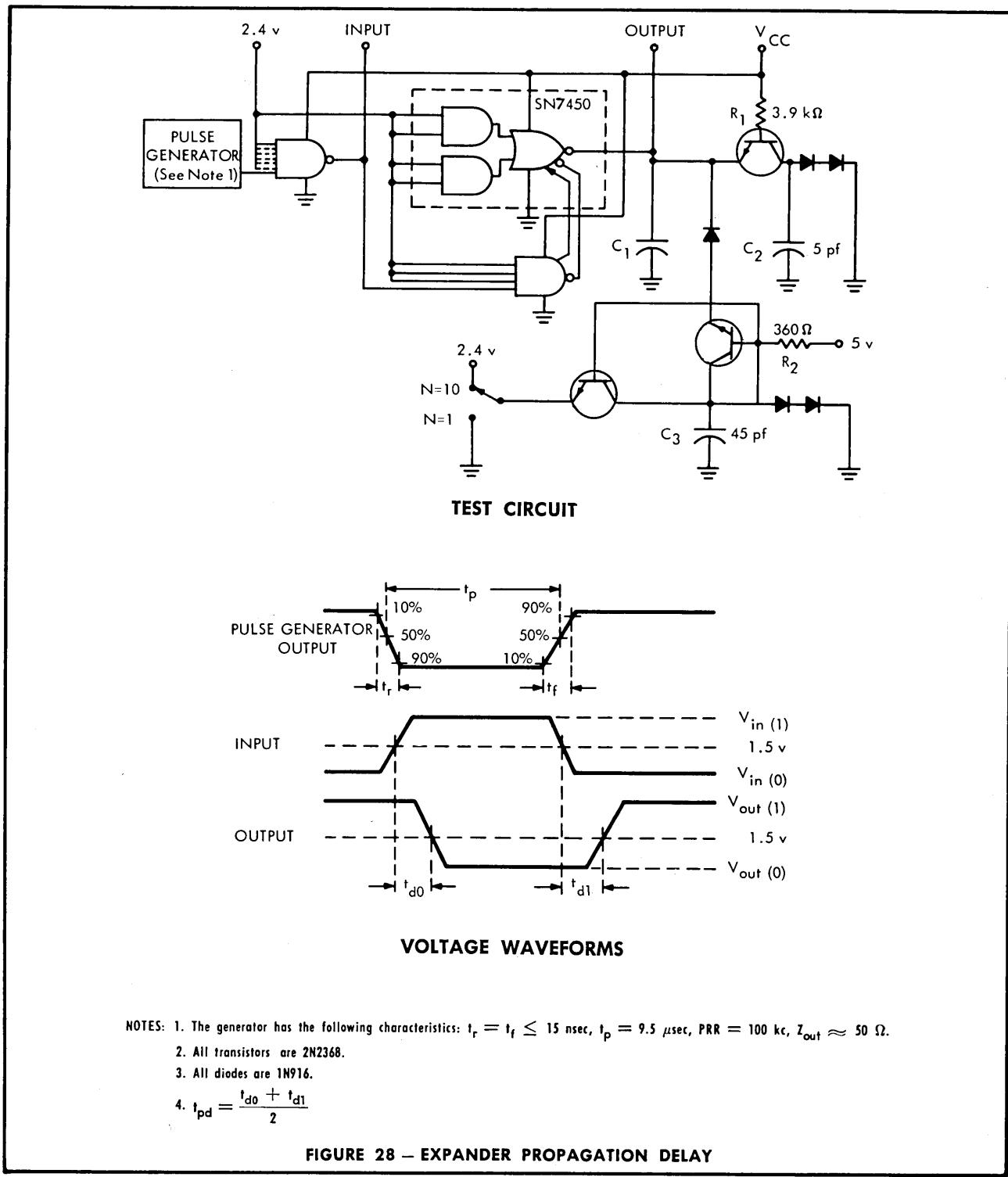
4. Test SN7440 with R₂ = 100 Ω, C₃ = 145 pF, N = 30 for t_{d0}, and N = 1 for t_{d1}.

$$5. t_{pd} = \frac{t_{d0} + t_{d1}}{2}$$

FIGURE 27 — GATE PROPAGATION DELAY

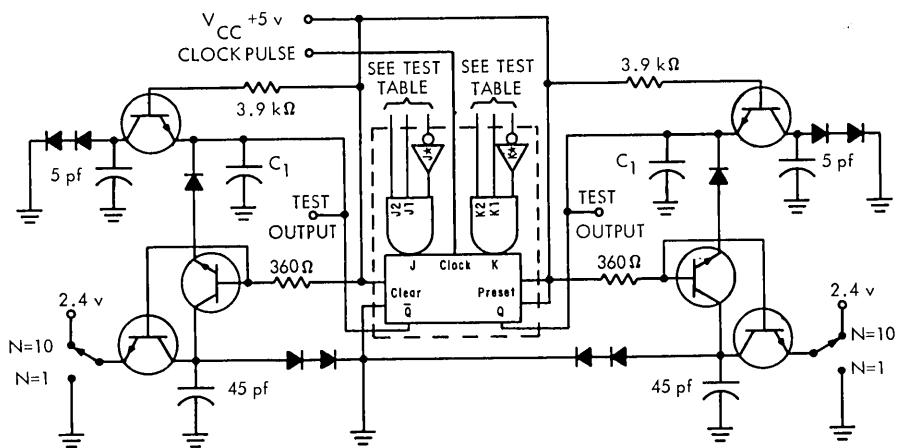
PARAMETER MEASUREMENT INFORMATION

switching characteristics (continued)



PARAMETER MEASUREMENT INFORMATION

switching characteristics (continued)

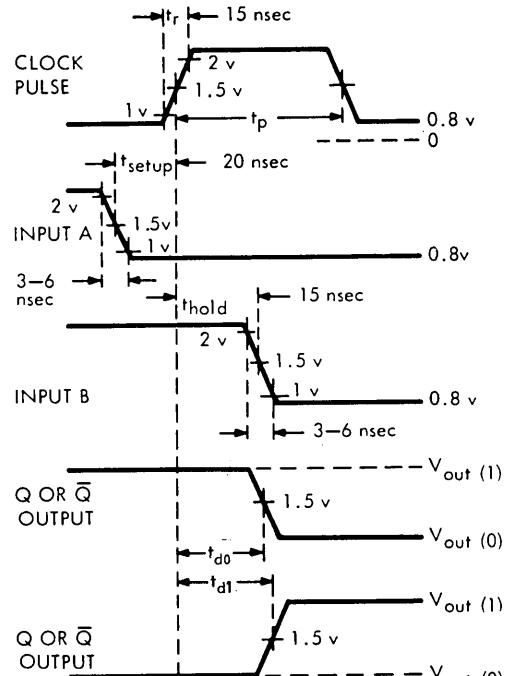


TEST CIRCUIT

TEST TABLE					
TEST NO.	TEST	INPUT A	INPUT B	+2.4 v	GND
1	$t_{d0} (\bar{Q})$	J★	J1, J2	K1, K2	K★
2	$t_{d1} (\bar{Q})$	K★	K1, K2	J1, J2	J★
3	$t_{d0} (Q)$	K★	K1, K2	J1, J2	J★
4	$t_{d1} (Q)$	J★	J1, J2	K1, K2	K★

NOTES: 1. All transistors are 2N2368.

2. All diodes are 1N916.

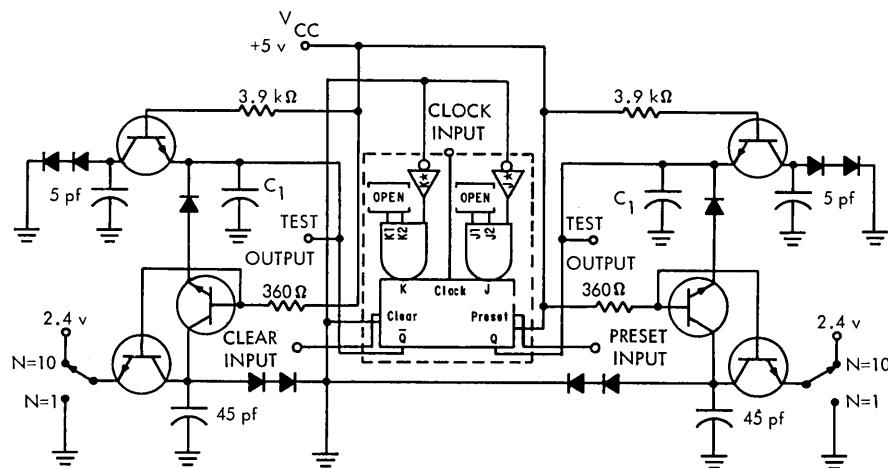


VOLTAGE WAVEFORMS

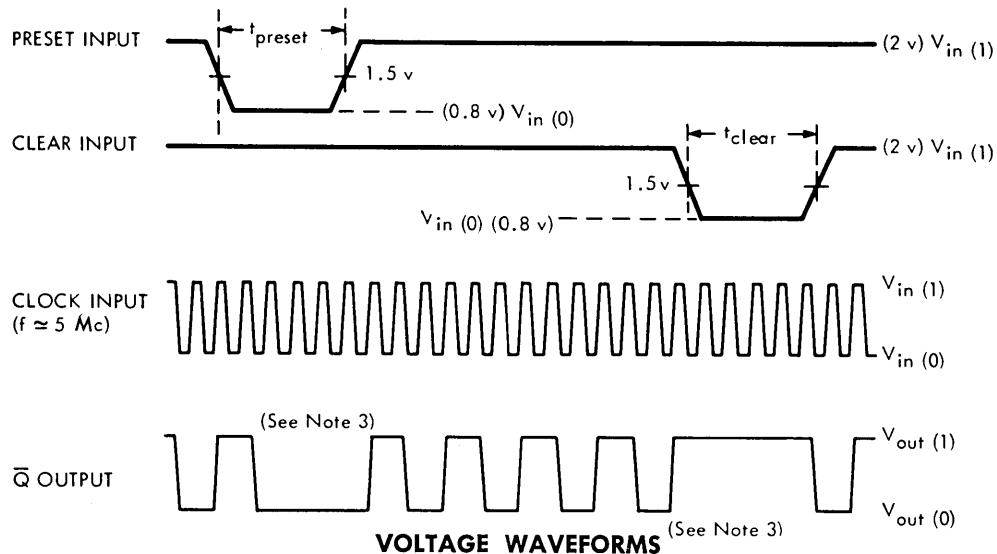
FIGURE 29 — FLIP-FLOP SWITCHING-TIME

PARAMETER MEASUREMENT INFORMATION

switching characteristics (continued)



TEST CIRCUIT



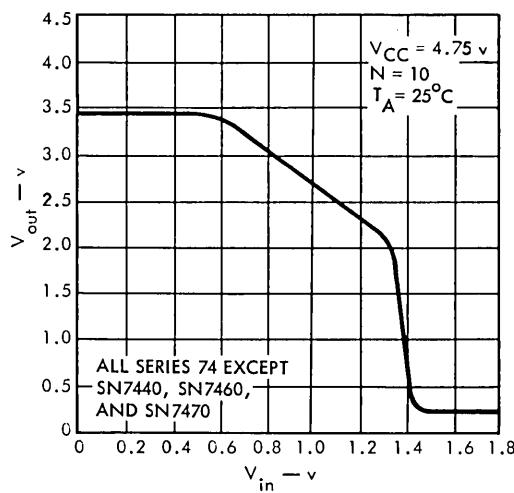
NOTES: 1. All transistors are 2N2368.
 2. All diodes are 1N916.
 3. Clock input of 5 Mc is used to verify that preset or clear input inhibits the clock function.

FIGURE 30 — PRESET/CLEAR TIME

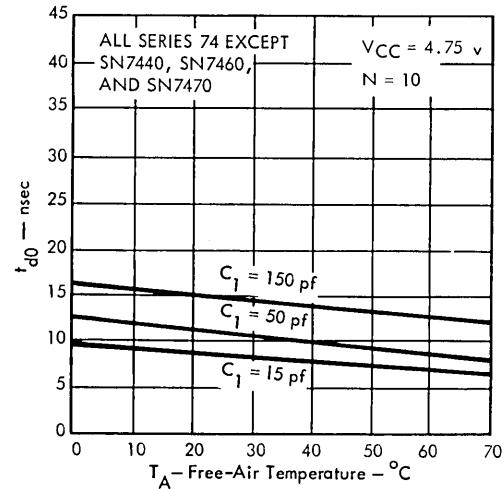
SERIES 74
SOLID CIRCUIT[®] SEMICONDUCTOR NETWORKS

TYPICAL CHARACTERISTICS

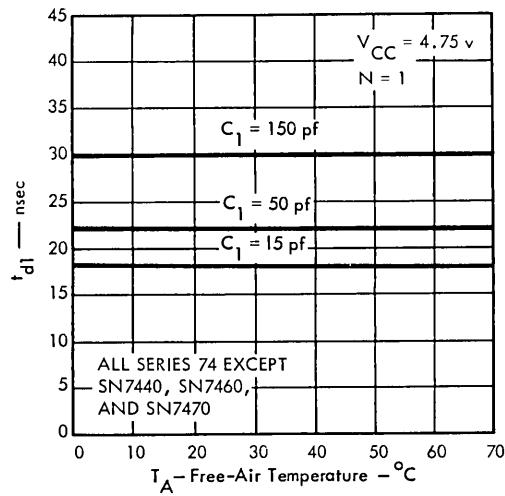
OUTPUT VOLTAGE vs INPUT VOLTAGE



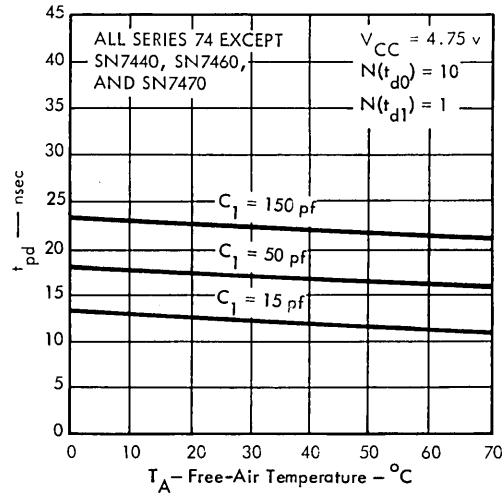
PROPAGATION TIME TO LOGICAL 0 vs TEMPERATURE



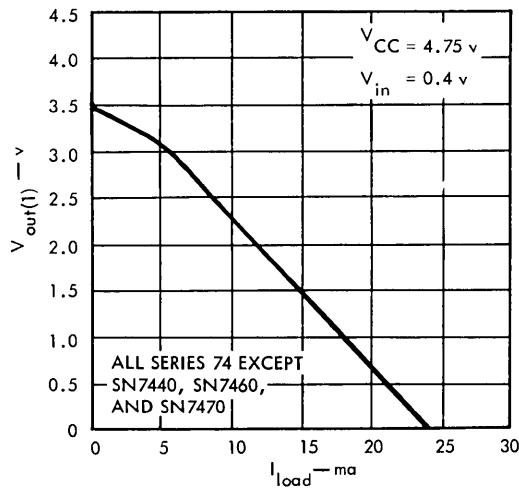
PROPAGATION TIME TO LOGICAL 1 vs TEMPERATURE



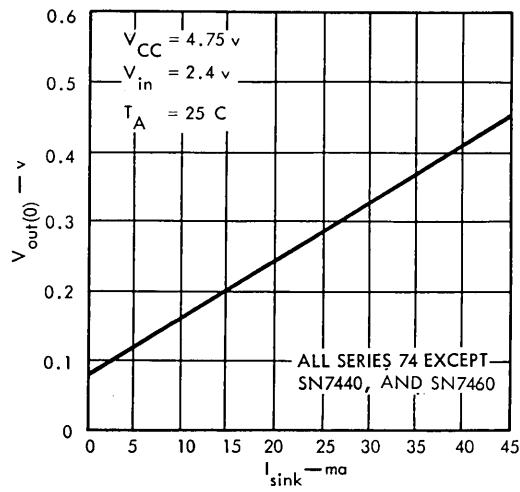
PROPAGATION DELAY TIME vs TEMPERATURE



OUTPUT VOLTAGE vs LOAD CURRENT



OUTPUT VOLTAGE vs SINK CURRENT



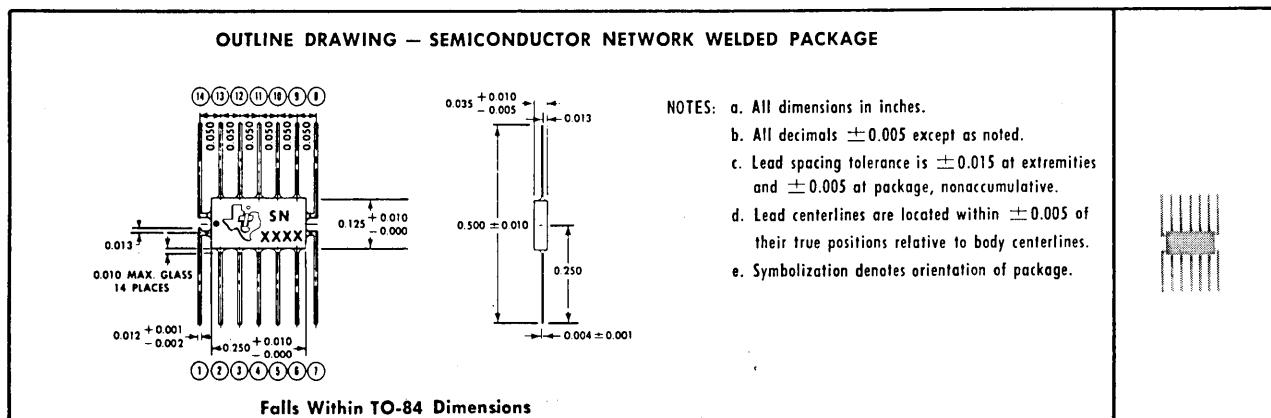
SERIES 74 SOLID CIRCUIT® SEMICONDUCTOR NETWORKS†

MECHANICAL DATA

general

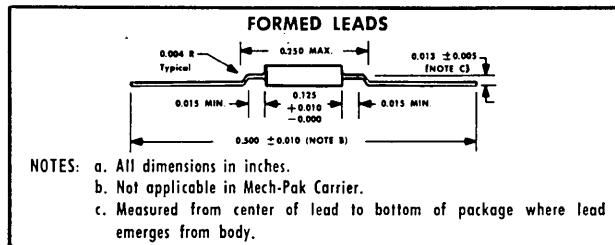
SOLID CIRCUIT semiconductor networks are mounted in a glass-to-metal hermetically sealed, welded package. Package body and leads are gold-plated F-15‡ glass-sealing alloy. Approximate weight is 0.1 gram. All external surfaces are

metallic and are insulated from leads and circuit. All Series 74 networks are available with formed leads, insulator attached, and/or mounted in a Mech-Pak carrier.



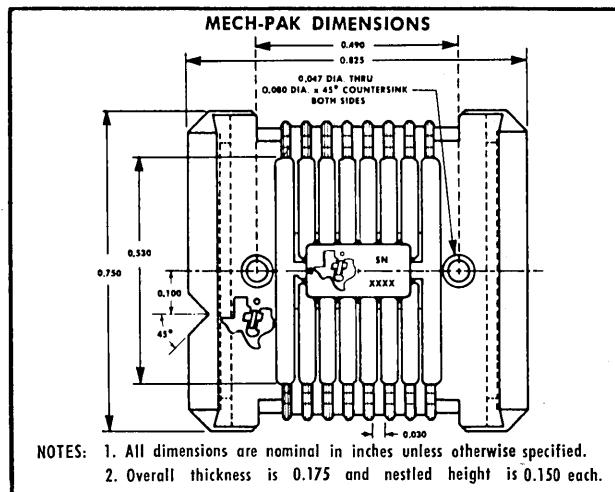
leads

Gold-plated F-15‡ leads require no additional cleaning or processing when used in soldered or welded assembly. Formed leads are available to facilitate planar mounting of networks on flat circuit boards. Standard lead length is 0.185 inches. Networks can be removed from Mech-Pak carriers with lead lengths up to 0.185 inches.



insulator

An insulator, secured to the back surface of the package, permits mounting networks on circuit boards which have conductors passing beneath the package. The insulator is 0.0025 inches thick and has an insulation resistance of 10 megohms at 25°C.



mech-pak carrier

The Mech-Pak carrier facilitates handling the network, and is compatible with automatic equipment used for testing and assembly. The carrier is particularly appropriate for mechanized assembly operations and will withstand temperatures of 125°C for indefinite periods.

ordering instructions

Variations in mechanical configuration of semiconductor networks are identified by suffix numbers shown in a table at the right.

	NO MECH-PAK CARRIER				MECH-PAK CARRIER			
Lead Length	0.185 inch				Not Applicable			
Formed Leads	No	No	Yes	Yes	No	No	Yes	Yes
Insulators	No	Yes	No	Yes	No	Yes	No	Yes
Ordering Suffix	None	-6	-7	-1	-2	-3	-4	-5

†Patented by Texas Instruments Incorporated.

‡F-15 is the ASTM designation for an iron-nickel-cobalt alloy containing nominally 53% iron, 29% nickel, and 17% cobalt.

